

PROCEEDINGS OF SPIE

# ***Penetrating Radiation Systems and Applications XIII***

**Gary P. Grim  
H. Bradford Barber**  
*Editors*

**13–15 August 2012  
San Diego, California, United States**

*Sponsored and Published by*  
SPIE

**Volume 8509**

Proceedings of SPIE 0277-786X, v. 8509

SPIE is an international society advancing an interdisciplinary approach to the science and application of light.

Penetrating Radiation Systems and Applications XIII, edited by Gary P. Grim, H. Bradford Barber, Proc. of SPIE Vol. 8509,  
850901 · © 2012 SPIE · CCC code: 0277-786X/12/\$18 · doi: 10.1117/12.2008654

Proc. of SPIE Vol. 8509 850901-1

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Author(s), "Title of Paper," in *Penetrating Radiation Systems and Applications XIII*, edited by Gary P. Grim, H. Bradford Barber, Proceedings of SPIE Vol. 8509 (SPIE, Bellingham, WA, 2012) Article CID Number.

ISSN: 0277-786X

ISBN: 9780819492265

Published by

**SPIE**

P.O. Box 10, Bellingham, Washington 98227-0010 USA

Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445

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